



# FDFMA2P853

# Integrated P-Channel PowerTrench® MOSFET and Schottky Diode

# **General Description**

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features a MOSFET with low on-state resistance and an independently connected low forward voltage schottky diode for minimum conduction losses.

The MicroFET 2x2 package offers exceptional thermal performance for it's physical size and is well suited to linear mode applications.



# **Features**

### MOSFET:

■ -3.0 A, -20V.  $R_{DS(ON)} = 120 \text{ m}\Omega$  @  $V_{GS} = -4.5 \text{ V}$ 

 $R_{DS(ON)} = 160 \text{ m}\Omega$  @  $V_{GS} = -2.5 \text{ V}$ 

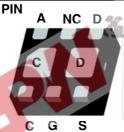
 $R_{DS(ON)} = 240 \text{ m}\Omega$  @  $V_{GS} = -1.8 \text{ V}$ 

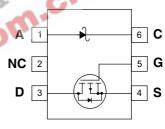
# Schottky:

V<sub>F</sub> < 0.46 V @ 500 mA

- Low Profile 0.8 mm maximun in the new package MicroFET 2x2 mm
- RoHS Compliant







# Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V <sub>DSS</sub>	MOSFET Drain-Source Voltage		-20	V	
V <sub>GSS</sub>	MOSFET Gate-Source Voltage		±8	V	
	Drain Current -Continuous	(Note 1a)	-2.2	Λ.	
ID	-Pulsed		-6	— A	
$V_{RRM}$	Schottky Repetitive Peak Reverse voltage		30	V	
Io	Schottky Average Forward Current	(Note 1a)	1	Α	
D	Power dissipation for Single Operation	(Note 1a)	1.4	w	
$P_{D}$	Power dissipation for Single Operation	(Note 1b)	0.7		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C	

# **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	86	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	173	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1c)	86	- C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1d)	140	

# **Package Marking and Ordering Information**

Device Marking	Device	Reel Size	Tape Width	Quantity
.853	FDFMA2P853	7inch	8mm	3000 units

Symbol	Parameter	Test Co	nditions	Min	Тур	Max	Units
Off Char	acteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 V$ , $I_D$ :	= –250 μA	-20			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = -250  \mu A,  \text{Refe}$	erenced to 25°C		-12		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V},  V_{G}$	s = 0 V			-1	μА
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 8 \text{ V},  V_{D}$	s = 0 V			±100	nA
On Char	acteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D$	= –250 μA	-0.4	-0.7	-1.3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$ , Refe			2		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V},  I_D : V_{GS} = -2.5 \text{ V},  I_D : V_{GS} = -1.8 \text{ V},  I_D : V_{GS} = -4.5 \text{ V},  I_D = -4.5  $	= –2.5 A = –1.0 A		90 120 172 118	120 160 240 160	mΩ
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{D}$	<sub>S</sub> = -5 V	-20			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 \text{ V},  I_D = -5 \text{ V}$		.0	7		S
Dynamic	Characteristics	•	6	75			
C <sub>iss</sub>	Input Capacitance	$V_{DS} = -10 \text{ V},  V_{CS}$	<sub>is</sub> = 0 V.	_1	435		pF
Coss	Output Capacitance	f = 1.0 MHz	2 12	C .	80		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	36	3 -40		45		pF
Switchin	g Characteristics (Note 2)		60,	•		•	
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_D = -10 \text{ V}$	=-1 A,		9	18	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{G}$	<sub>EN</sub> = 6 Ω		11	19	ns
t <sub>d(off)</sub>	Turn-Off Delay Time				15	27	ns
t <sub>f</sub>	Turn-Off Fall Time				6	12	ns
$\overline{Q_g}$	Total Gate Charge	$V_{DS} = -10 \text{ V},  I_{D} = -3.0 \text{ A}, \ V_{GS} = -4.5 \text{ V}$			4	6	nC
Q <sub>gs</sub>	Gate-Source Charge				0.8		nC
$Q_{gd}$	Gate-Drain Charge				0.9		nC
Drain-So	ource Diode Characteristics	and Maximum	Ratings				
Is	Maximum Continuous Drain–Source					-1.1	Α
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 0$	= -1.1 A (Note 2)		-0.8	-1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	$I_F = -3.0 \text{ A},$			17		ns
Q <sub>rr</sub>	Diode Reverse Recovery Charge	dl <sub>F</sub> /dt = 100 A/μs			6		nC
Schottky	Diode Characteristics						
I <sub>R</sub>	Reverse Leakage	V <sub>R</sub> = 5 V	T <sub>J</sub> = 25°C		9.9	50	μА
			T <sub>J</sub> = 125°C		2.3	10	mA
I <sub>R</sub>	Reverse Leakage	V <sub>R</sub> = 20 V	T <sub>J</sub> = 25°C		9.9	100	μА
			T <sub>J</sub> = 85°C		0.3	1	mA
			T <sub>J</sub> = 125°C		2.3	10	mA
$V_F$	Forward Voltage	I <sub>F</sub> = 500mA	T <sub>J</sub> = 25°C		0.4	0.46	V
			T <sub>J</sub> = 125°C		0.3	0.35	
$V_F$	Forward Voltage	I <sub>F</sub> = 1A	T <sub>J</sub> = 25°C		0.5	0.55	V
			T <sub>J</sub> = 125°C	1	0.49	0.54	

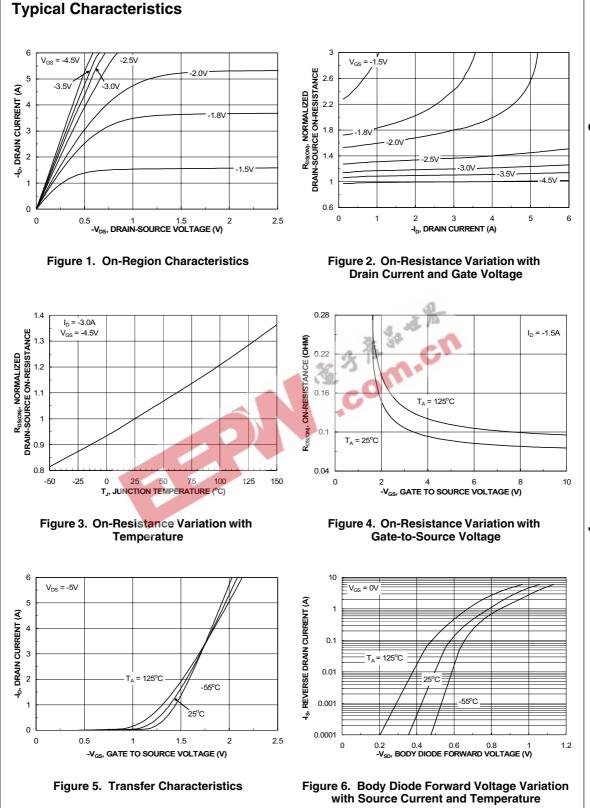
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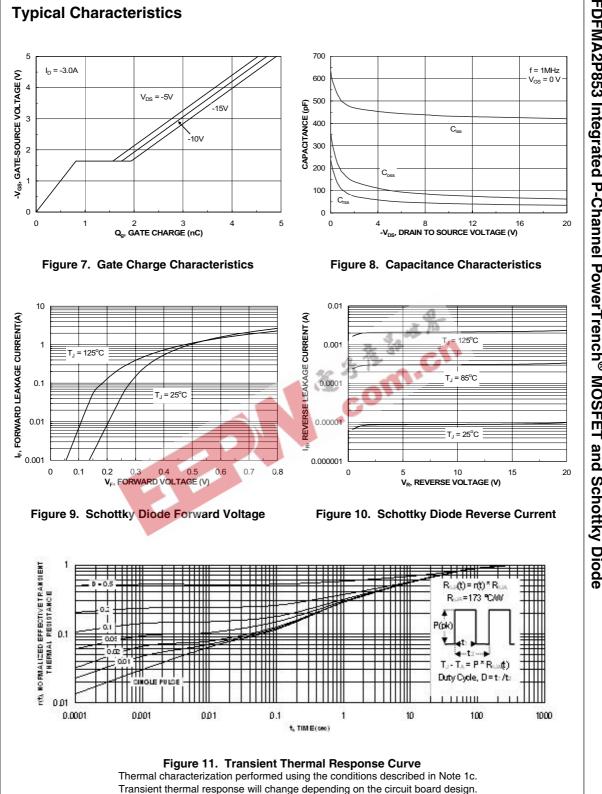
# Electrical Characteristics T<sub>A</sub> = 25°C unless otherwise noted

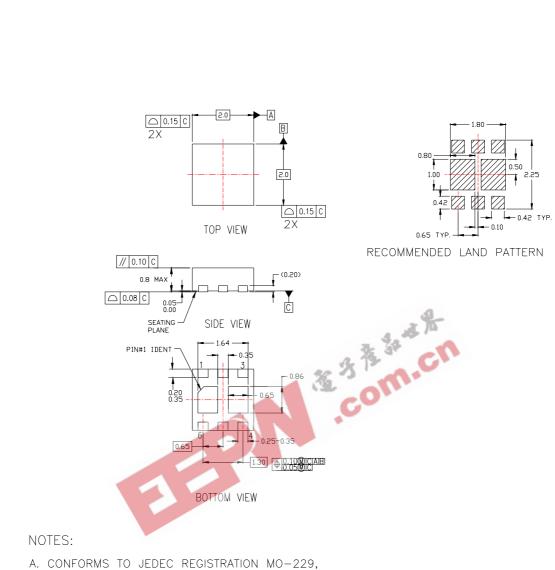
- 1.  $R_{\rm BJA}$  is determined with the device mounted on a 1 in<sup>2</sup> oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\rm BJC}$  is guaranteed by design while  $R_{\theta, JA}$  is determined by the user's board design.
  - (a) MOSFET  $R_{\theta JA} = 86^{\circ}$ C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
  - (b) MOSFET  $R_{\theta JA}$  = 173°C/W when mounted on a minimum pad of 2 oz copper
  - (c) Schottky  $R_{\theta JA} = 86^{\circ}$ C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
  - (d) Schottky  $R_{\theta JA}$  = 140°C/W when mounted on a minimum pad of 2 oz copper



2. Pulse Test: Pulse Width <  $300\mu s$ , Duty Cycle < 2.0%







- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC, DATED 11/2001
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

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#### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
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